

UNITED STATES PATENT AND TRADEMARK OFFICE
BEFORE THE PATENT TRIAL AND APPEAL BOARD

MICRON TECHNOLOGY, INC.,
Petitioner

v.

YANGTZE MEMORY TECHNOLOGIES COMPANY, LTD.,
Patent Owner

Case No. PGR2025-00021
U.S. Patent No. 12,010,838 B2

**PETITIONER'S OBJECTIONS TO
PATENT OWNER'S RESPONSE EVIDENCE**

Pursuant to 37 C.F.R. § 42.64(b)(1), Petitioner hereby objects to the exhibits cited and relied upon in Patent Owner's November 26, 2025 response on the following grounds.

Patent Owner objected to a number of exhibits as purportedly containing "inadmissible hearsay," "as not properly authenticated," or on other grounds. *See generally* Paper 23. Patent Owner's objections are overbroad and do not provide Petitioner enough information to inform it of the alleged deficiencies. Further, Patent Owner improperly objects without providing any rationale that any of the purportedly objectional exhibits is anything other than what it purports to be, or was published on anything other than the date indicated. Should the Board sustain Patent Owner's overbroad and improper objections, Petitioner provides similar objections below to Patent Owner's evidence. For each objected to exhibit, the pertinent Federal Rule of Evidence ("FRE") or other rule that gives rise to the objection is provided, along with a brief summary of the basis of the objection.

1. Ex. 2019 – "Declaration of Constantinos Giapis in Support of Patent Owner's Response": FRE 802, 901. This exhibit improperly cites to and quotes inadmissible Exs. 2025-2027 and 2042-2044.

2. Ex. 2025 – "EFY Bureau, *At 20nm, Chips Have Features Sized Ten Times Smaller Than the Wavelength of Laser Used in Lithography*, electronicsforu.com (Dec. 4, 2014)": FRE 802. The exhibit includes out of court,

hearsay statements that are being improperly cited to establish the truth of the matter asserted. Patent Owner has not established that any hearsay exception applies. **FRE 901.** Patent Owner has failed to properly authenticate the information in this exhibit. Among other things, it is unclear from the record when and where the exhibit published.

3. Ex. 2026 – “Press Release, ASML, ASML Extends ArF Leadership (Dec. 6, 2006)”: **FRE 802.** The exhibit includes out of court, hearsay statements that are being improperly cited to establish the truth of the matter asserted. Patent Owner has not established that any hearsay exception applies. **FRE 901.** Patent Owner has failed to properly authenticate the information in this exhibit. Among other things, it is unclear from the record when and where the exhibit published.

4. Ex. 2027 – “ASML, Light and Lasers”: **FRE 802.** The exhibit includes out of court, hearsay statements that are being improperly cited to establish the truth of the matter asserted. Patent Owner has not established that any hearsay exception applies. **FRE 901.** Patent Owner has failed to properly authenticate the information in this exhibit. Among other things, it is unclear from the record when and where the exhibit published.

5. Ex. 2042 – “A.E.T. Kuiper et al., Oxidation Behaviour of LPCVD Silicon Oxynitride Films, 33/34 APPLIED SURFACE SCI. 757 (1988)”: **FRE 802.** The exhibit includes out of court, hearsay statements that are being improperly

cited to establish the truth of the matter asserted. Patent Owner has not established that any hearsay exception applies. **FRE 901.** Patent Owner has failed to properly authenticate the information in this exhibit. Among other things, it is unclear from the record when and where the exhibit published.

6. Ex. 2043 – “Yen-Po Lin & Jenn-Gwo Hwu, Quality Improvement in LPCVD Silicon Nitrides by Anodic and Rapid Thermal Oxidations, 7 ELECTROCHEMICAL SOLID-STATE LETTERS G87 (2004)”: **FRE 802.**

The exhibit includes out of court, hearsay statements that are being improperly cited to establish the truth of the matter asserted. Patent Owner has not established that any hearsay exception applies. **FRE 901.** Patent Owner has failed to properly authenticate the information in this exhibit. Among other things, it is unclear from the record when and where the exhibit published.

7. Ex. 2044 – “X. Y. Chen et al., Annealing and Oxidation of Silicon Oxide Films Prepared By Plasma-Enhanced Chemical Vapor Deposition, 97 J. APPLIED PHYSICS 014913 (2005)”: **FRE 802.** The exhibit includes out of court, hearsay statements that are being improperly cited to establish the truth of the matter asserted. Patent Owner has not established that any hearsay exception applies. **FRE 901.** Patent Owner has failed to properly authenticate the information in this exhibit. Among other things, it is unclear from the record when and where the exhibit published.

Respectfully submitted,

ORRICK, HERRINGTON & SUTCLIFFE LLP

Dated: December 4, 2025

/K. Patrick Herman/

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CERTIFICATE OF SERVICE

The undersigned hereby confirms that the foregoing paper was caused to be served on December 4, 2025 via email upon the following counsel of record for

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